



Application Serial No. 09/677,478
Supplemental IDS

MI22-1544

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/677,478
Filing Date October 2, 2000
Inventor Guy T. Blalock et al.
Assignee Micron Technology, Inc.
Group Art Unit 1765
Examiner Lan Vinh
Attorney's Docket No. MI22-1544
Title: Plasma Etching Methods

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Reference -- See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Dated: 6-26-06

By: 
D. Brent Kenady
Reg. No. 40,045

<p style="text-align: center;">U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE</p> <p style="text-align: center;">JUN 26 2006 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>					ATTY. DOCKET NO. MI22-1544		SERIAL NO. 09/677,478	
					APPLICANT Guy T. Blalock et al.			
					FILING DATE October 2, 2000		GROUP 1765	
U.S. PATENT DOCUMENTS								
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,800,561	10/04	Allen III	438	714		
	AB	6,878,300 B2	04/05	Allen III	216	058		
	AC							
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FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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